

IN THE CLAIMS:

Please amend claims 1 and 4-5, and add new claims 6-7 as follows:

1. (Currently Amended) A semiconductor integrated circuit device comprising:
 - first and second circuit blocks;
 - an interface checker ~~[[to]]~~ which is installed on the semiconductor integrated circuit device and monitors whether waveforms of signals between the first and second circuit blocks conform to an interface specification of a design data of the first circuit block; and
 - an external output pin ~~[[to]]~~ which outputs a result of a monitoring of the interface checker ~~to an external~~ outside of the semiconductor integrated circuit device.
2. (Original) The semiconductor integrated circuit device according to claim 1,
 - wherein the external output pin outputs a first value indicating a conformity of the waveforms to the interface specification or a second value indicating a nonconformity of the waveforms to the interface specification.
3. (Original) The semiconductor integrated circuit device according to claim 1,
 - wherein the interface specification describes timing information in synchronization with a clock signal.
4. (Currently Amended) A design method of a semiconductor integrated circuit device comprising~~[[;]]~~:
 - providing a design data and an interface specification of the design data;
 - generating a synthesizable interface checker in accordance with the interface specification;
 - producing a semiconductor integrated circuit device including a first ~~[[logic]]~~ circuit block according to the design data and the interface checker according to the synthesizable interface checker; and
 - using the interface checker installed on the semiconductor integrated circuit device to monitor~~[[ing]]~~ whether waveforms of signals between the first circuit block and another circuit block conform to the interface specification of the design data.

5. (Currently Amended) The design method of the semiconductor integrated circuit device according to claim 4, further comprising[[:]]:
outputting a first value indicating a conformity of the waveforms to the interface specification or a second value indicating a nonconformity of the waveforms to the interface specification ~~to an external~~ outside of the semiconductor integrated circuit device.
6. (New) The semiconductor integrated circuit device according to claim 1, wherein the interface checker is incorporated into the semiconductor integrated circuit device for logic synthesis and verification.
7. (New) The design method of the semiconductor integrated circuit device according to claim 4, further comprising:
generating and verifying a logic model of the semiconductor integrated circuit device with the interface checker incorporated therein.